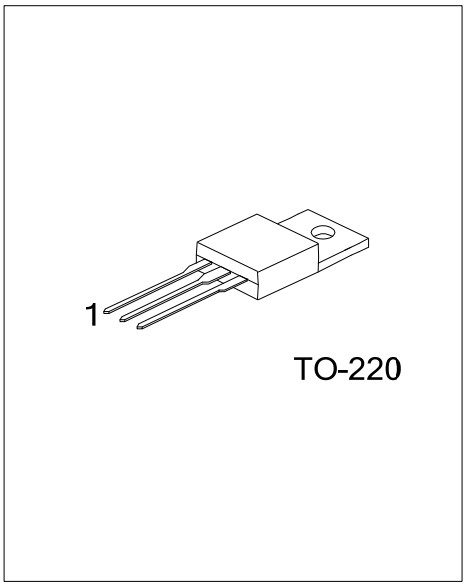
UT80N03

Preliminary | ***Power MOSFET***

80A, 30V N-CHANNEL POWER MOSFET



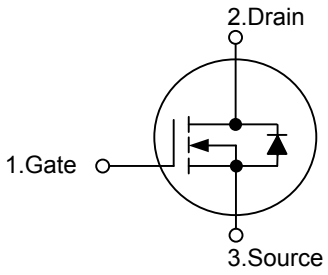
■ DESCRIPTION

The UTC **UT80N03** is a high voltage MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and have a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient AC to DC converters and bridge circuits.

■ FEATURES

* $R_{DS(ON)} \leq 4.8\ m\Omega$ @ V_{GS}=10V, I_D=40A
  $R_{DS(ON)} \leq 7.2\ m\Omega$ @ V_{GS}=4.5V, I_D=40A
* Fast switching capability
* Avalanche energy specified
* Improved dv/dt capability, high ruggedness

■ SYMBOL



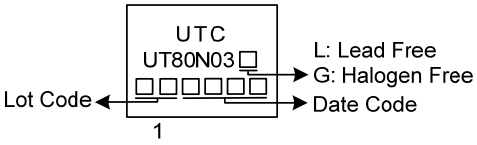
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
UT80N03L-TA3-T	UT80N03G-TA3-T	TO-220	G	D	S	Tube

Note: Pin Assignment: G: Gate D: Drain S: Source

UT80N03G-TA3-T (1)Packing Type (2)Package Type (3)Green Package	(1) T: Tube (2) TA3: TO-220 (3) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING



■ ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	30	V
Gate-Source Voltage		V_{GSS}	±20	V
Drain Current	Continuous	I_D	80	A
	Pulsed (Note 2)	I_{DM}	160	A
Peak Diode Recovery dv/dt (Note 3)		dv/dt	1.05	V/ns
Avalanche energy	Single Pulsed (Note 3)	E_{AS}	171	mJ
Power Dissipation		P_D	70	W
Junction Temperature		T_J	+150	°C
Storage Temperature		T_{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating : Pulse width limited by maximum junction temperature.
3. L=0.1mH, I_{AS}=58A, V_{DD}=30V, R_G=25Ω, Starting T_J = 25°C
4.I_{SD} ≤ 30A, di/dt ≤200A/μs, V_{DD}≤ BV_{DSS}, Starting T_J= 25°C

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction-to-Ambient	θ_{JA}	62.5	°C/W
Junction-to-Case	θ_{JC}	1.78	°C/W

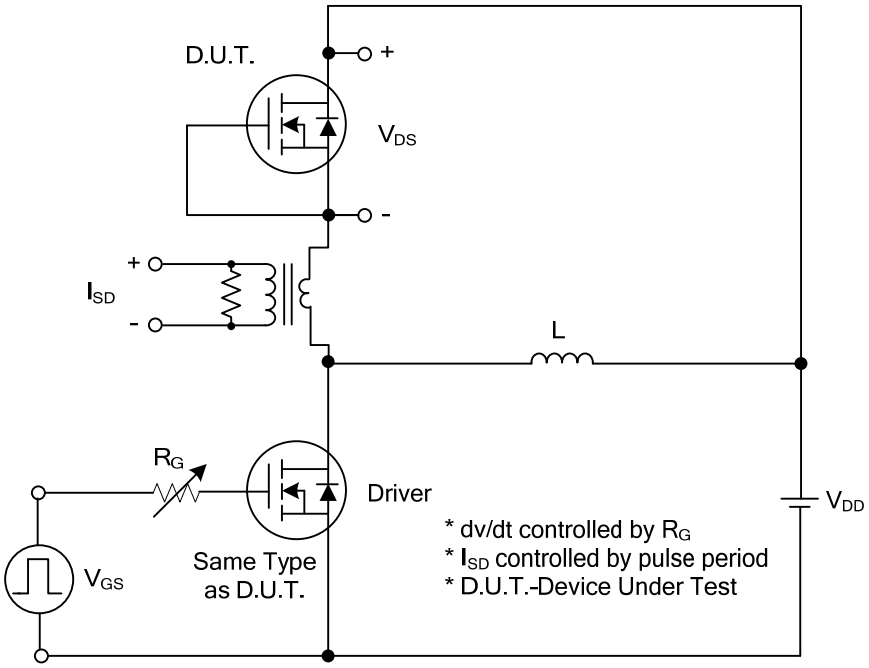
Note: Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.

■ ELECTRICAL CHARACTERISTICS (T_J=25°C, unless otherwise specified)

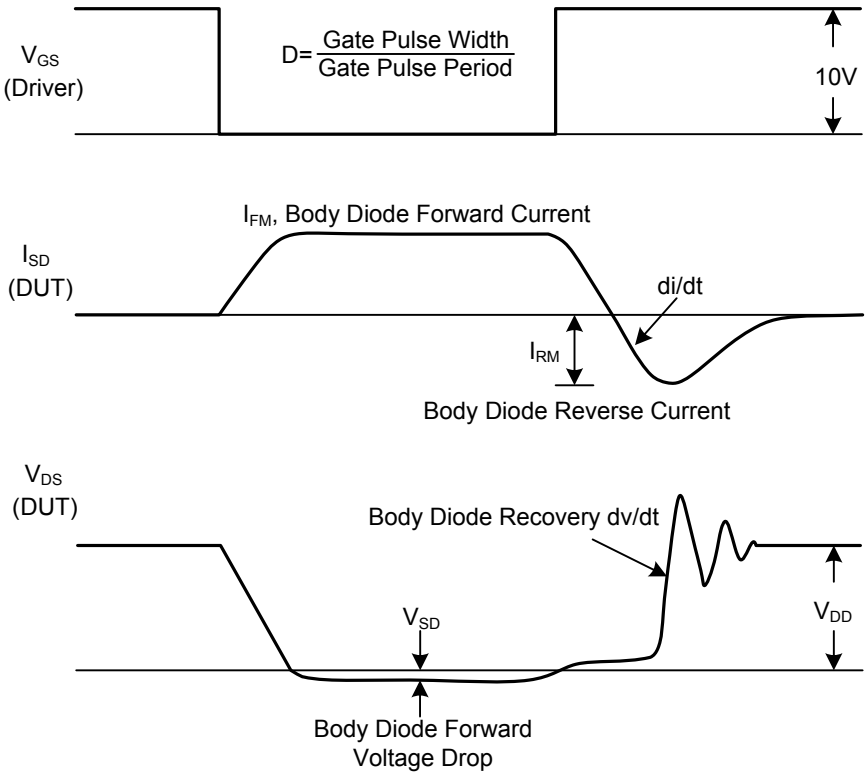
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	V_{GS}=0V, I_D=250μA	30			V
Drain-Source Leakage Current		I_{DSS}	V_{DS}=30V, V_{GS}=0V			1	μA
Gate-Source Leakage Current	Forward	I_{GSS}	V_{GS}=20V, V_{DS}=0V			100	nA
	Reverse		V_{GS}=-20V, V_{DS}=0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V_{DS}=V_{GS}, I_D=250μA	1.0		3.0	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	V_{GS}=10V, I_D=40A			4.8	mΩ
			V_{GS}=4.5V, I_D=40A			7.2	mΩ
DYNAMIC CHARACTERISTICS							
Input Capacitance		C_{ISS}	V_{DS}=25V, V_{GS}=0V, f=1MHz		2730		pF
Output Capacitance		C_{OSS}			520		pF
Reverse Transfer Capacitance		C_{RSS}			452		pF
SWITCHING CHARACTERISTICS							
Total Gate Charge (Note 1)		Q_G	V_{DS}=24V, V_{GS}=10V, I_D=80A, (Note 1, 2)		100		nC
Gate to Source Charge		Q_{GS}			11		nC
Gate to Drain Charge		Q_{GD}			31		nC
Turn-ON Delay Time (Note 1)		$t_{D(ON)}$	V_{DD}=100V, V_{GS}=10V, I_D=80A, R_G=3Ω (Note 1, 2)		12		ns
Rise Time		t_R			20		ns
Turn-OFF Delay Time		$t_{D(OFF)}$			50		ns
Fall-Time		t_F			32		ns
DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS							
Maximum Body-Diode Continuous Current		I_S				80	A
Maximum Body-Diode Pulsed Current (Note 1)		I_{SM}				160	A
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I_S=80A, V_{GS}=0V			1.4	V
Body Diode Reverse Recovery Time		t_{rr}	I_S=30A, V_{GS}=0V		220		ns
Body Diode Reverse Recovery Charge		Q_{rr}	dI_F/dt=100A/μs		580		nC

Notes: 1. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

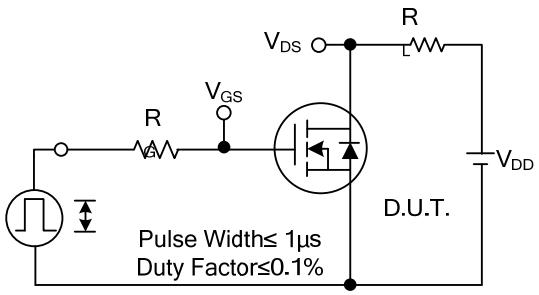


Peak Diode Recovery dv/dt Test Circuit

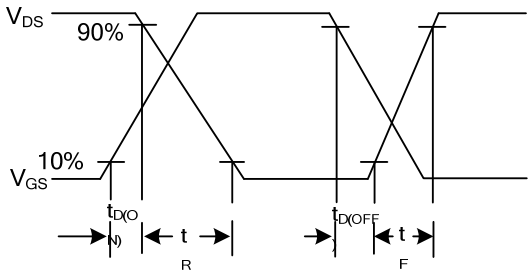


Peak Diode Recovery dv/dt Waveforms

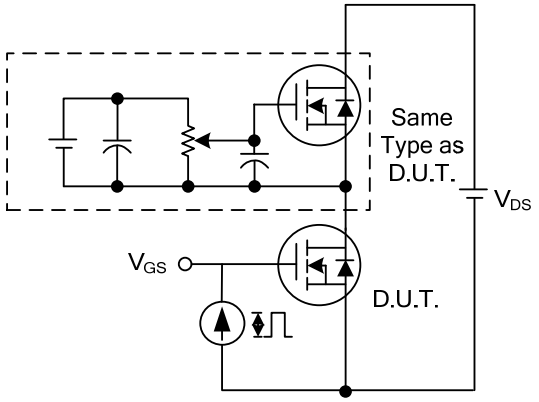
■ TEST CIRCUITS AND WAVEFORMS



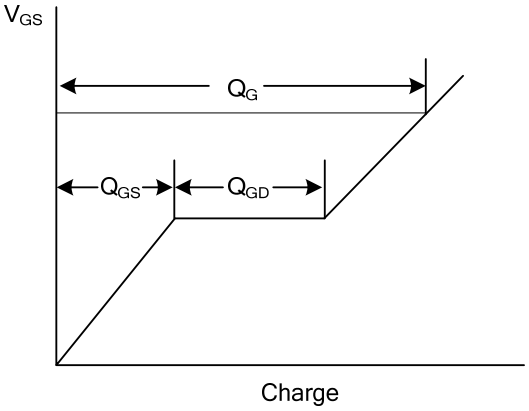
Switching Test Circuit



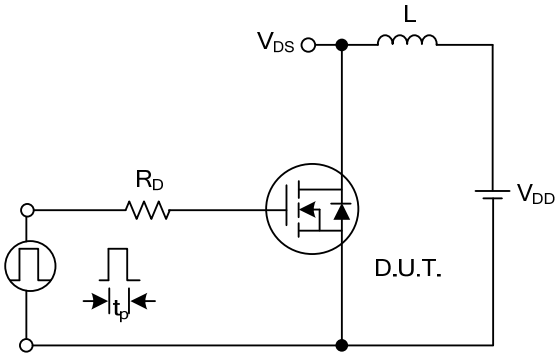
Switching Waveforms



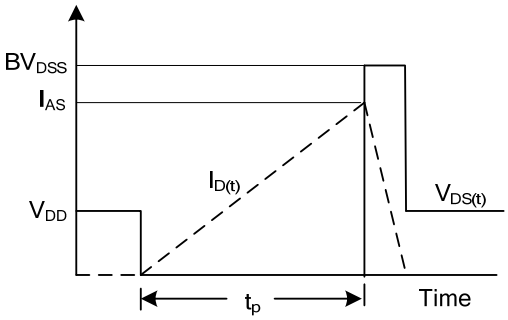
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms